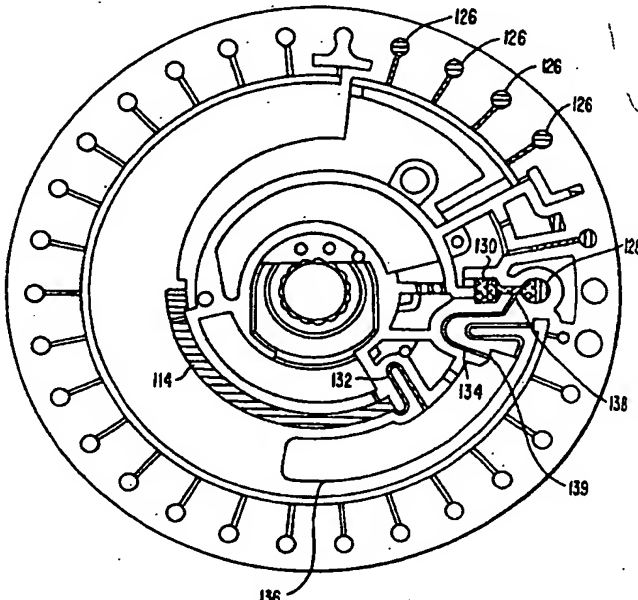
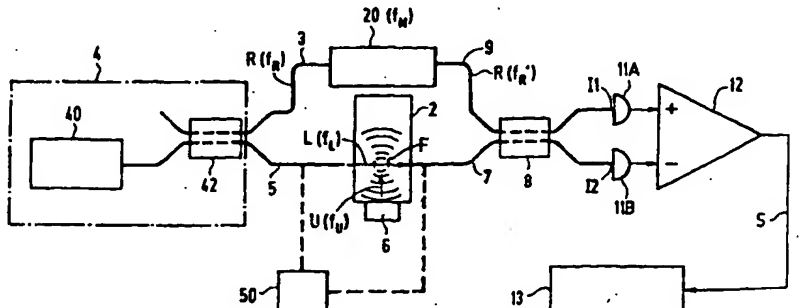


G01N

<p>(21) Int. Application Number: PCT/US95/07145</p> <p>(22) Int. Filing Date: 5 June 1995 (05.06.95)</p>	<p>(51) International Patent Classification ⁶ : G01N 21/07</p>	<p>(11) Int. Publication Number: WO 95/33986</p> <p>(43) Int. Publication Date: 14 December 1995 (14.12.95)</p>
<p>(30) Priority Data: 08/254,406 6 June 1994 US (06.06.94)</p> <p>(71) Applicant: ABAXIS, INC. [US/US]; 1320 Chesapeake Terrace, Sunnyvale, CA 94089 (US).</p> <p>(72) Inventors: KOPF-SILL, Anne, R.; 30 Minoca Road, Portola Valley, CA 94028 (US). SCHEMBRI, Carol, T.; 3912 Marshall Avenue, San Mateo, CA 94403 (US).</p> <p>(74) Agents: BASTIAN, Kevin, L. et al.; Townsend and Townsend Khourie and Crew, Stuart Street Tower, 20th floor, One Market Plaza, San Francisco, CA 94105-1492, e (US).</p> <p>(81) Designated States: CA, JP, European patent (AT, BE, CH, DE, DK, ES, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).</p>	<p>(54) Title: MODIFIED SIPHONS FOR IMPROVED METERING PRECISION</p> <p>(57) Abstract</p> <p>The present invention provides force rotors for delivering a premeasured volume of liquid to a chamber in the rotor. In particular the rotors comprise siphons (134) for delivering a premeasured volume of liquid between a first and a second chamber (136) in the rotor. The siphons (134) of the invention are designed such that the inlet (138) of the siphon on the first chamber is radially outward of the siphon outlet (139) on the second chamber (136). The first chamber is emptied to a level equivalent to the radial position of the siphon outlet (139).</p> 	
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<p>(21) Int. Application Number: PCT/DE95/00673</p> <p>(22) Int. Filing Date: 23 May 1995 (23.05.95)</p>	<p>(51) International Patent Classification ⁶ : G01N 21/47, 21/59, A61B 5/00</p>	<p>(11) Int. Publication Number: WO 95/33987</p> <p>(43) Int. Publication Date: 14 December 1995 (14.12.95)</p>
<p>(30) Priority Data: P 44 19 900.7 7 June 1994 DE (07.06.94)</p> <p>(71) Applicant (for all designated States except US): SIEMENS AKTIENGESELLSCHAFT [DE/DE]; Wittelsbacherplatz 2, D-80333 München (DE).</p> <p>(72) Inventors; and (75) Inventors/Applicants (for US only): SÖLKNER, Gerald [AT/DE]; Naupliaallee 12, D-85521 Ottobrunn (DE). BARTELT, Hartmut [DE/DE]; Heerfleckenstrasse 38, D-91056 Erlangen (DE).</p> <p>(81) Designated States: JP, US, European patent (AT, BE, CH, DE, DK, ES, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).</p>	<p>(54) Title: METHOD AND DEVICE FOR IMAGING AN OBJECT USING LIGHT</p> 	
<p>(57) Abstract</p> <p>In the method proposed, examination light (L) and focussed ultrasonic radiation (U) are beamed into an object (2). After it has passed through the object (2), the examination light (L) is superimposed in an interferometer on reference light (R) which is coherent with the examination light (L). The intensity or amplitude of the resulting interference light (I) provides information for an image point which corresponds to the image of the part of the object (2) lying in the zone of focus (F) of the focussed ultrasonic radiation (U).</p>		
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